

N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^{a, e}	Q _g (Typ.)			
30	0.0063 at V _{GS} = 10 V	62	52nC			
	0.0135 at V _{GS} = 4.5 V	38	52110			

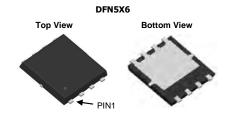
FEATURES

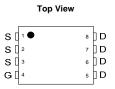
- DT-Trench Power MOSFET
- 100 % R_g and UIS Tested

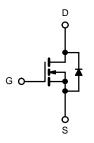


APPLICATIONS

- · Notebook PC Core
- VRM/POL







N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	30	\\		
Gate-Source Voltage	V _{GS}	± 20	V		
	T _C = 25 °C		62 ^{a, e}		
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C	I _D	50 ^e		
Continuous Diam Guirent (1) = 173 C)	T _A = 25 °C	'D	11 ^{b, c}	A	
	T _A = 70 °C		8.3 ^{b, c}	^	
Pulsed Drain Current	I _{DM}	186	7		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	56		
Single Pulse Avalanche Energy	L = 0.1 IIII1	E _{AS}	45	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	Is	62 ^{a, e}	A	
Continuous Source-Diam Diode Current	T _A = 25 °C	'8	2.32 ^{b, c}	_ ^	
	T _C = 25 °C		168 ^a		
Maximum Power Dissipation	T _C = 70 °C	PD	127	w	
	T _A = 25 °C	טי	3.25 ^{b, c}	VV	
	T _A = 70 °C		2.12 ^{b, c}		
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	48	60	°C/W		
Maximum Junction-to-Case	Steady State	R _{thJC}	0.8	1.2]		

Notes:

- a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 62 A.



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Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	$I_D = 250 \mu\text{A}$		35		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	10 – 200 μΛ		- 5.5		mv/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.8		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zara Cata Valtaga Drain Current	1	V _{DS} = 24 V, V _{GS} = 0 V			1	μA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 24 V, V _{GS} = 0 V, T _J = 55 °C			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	80			Α
	В	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		0.0063	0.0078	Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		0.0135	0.0165	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 30 A		125		S
Dynamic ^b						
Input Capacitance	C _{iss}			1850		
Output Capacitance	C _{oss}	V_{DS} = 24 V, V_{GS} = 0 V, f = 1 MHz		625		pF
Reverse Transfer Capacitance	C _{rss}			105		
Total Gate Charge	Qg	$V_{DS} = 24 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 30 \text{ A}$		52		nC
				35		
Gate-Source Charge	Q_{gs}	$V_{DS} = 24 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 20 \text{ A}$		19		
Gate-Drain Charge	Q_{gd}			23		
Gate Resistance	R _g	f = 1 MHz		1.5	2.5	Ω
Turn-On Delay Time	t _{d(on)}			30		ns
Rise Time	t _r	V_{DD} = 24 V, R_L = 0.555 Ω		15		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 30 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		78		
Fall Time	t _f			14		
Turn-On Delay Time	t _{d(on)}			60		
Rise Time	t _r	V_{DD} = 24 V, R_L = 0.625 Ω		165		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 20$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		55		
Fall Time	t _f			17		
Drain-Source Body Diode Characteristic	es					
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			62	A
Pulse Diode Forward Current ^a	I _{SM}				186	
Body Diode Voltage	V_{SD}	I _S = 10 A		0.7	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			52	73	ns
Body Diode Reverse Recovery Charge	Q _{rr}	L = 20 A di/dt = 100 A/us T = 25 °C		65	102	nC
Reverse Recovery Fall Time	t _a	$I_{\rm F} = 20$ A, di/dt = 100 A/µs, $I_{\perp} = 25$ °C I_{\perp}		27		
Reverse Recovery Rise Time	t _b			20		ns

Notes:

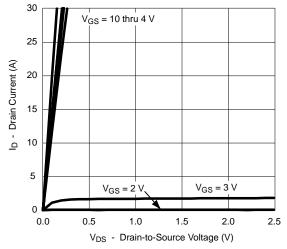
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

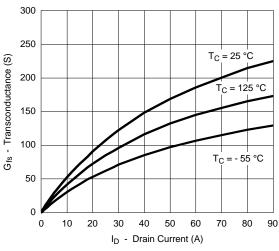




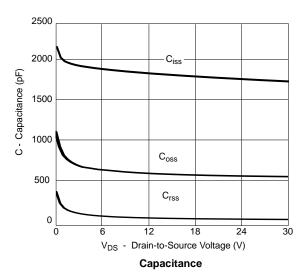
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

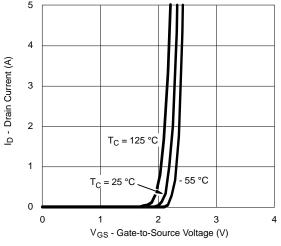


Output Characteristics

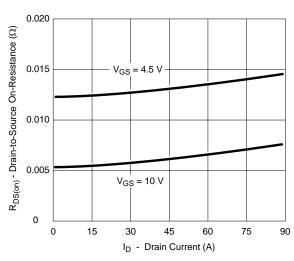


Transconductance

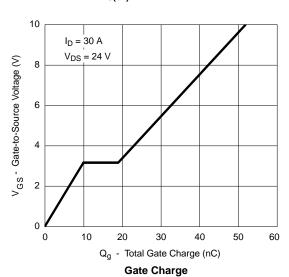




Transfer Characteristics

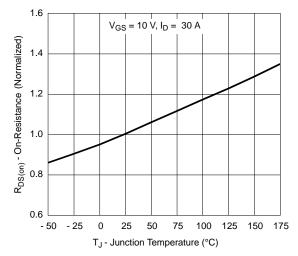


R_{DS(on)} vs. Drain Current

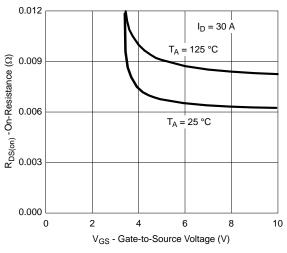




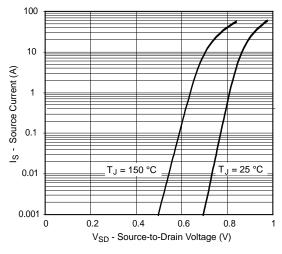
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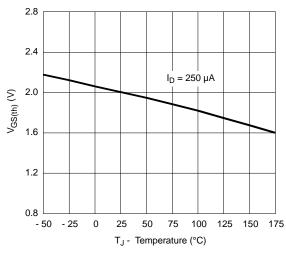
On-Resistance vs. Junction Temperature



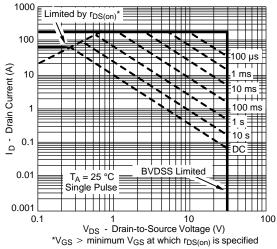
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



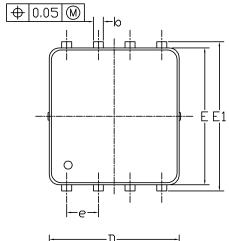
Threshold Voltage

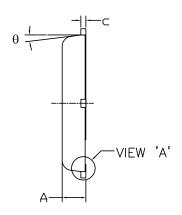


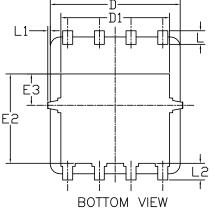
Safe Operating Area, Junction-to-Ambient

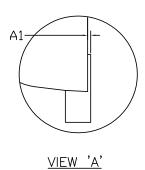






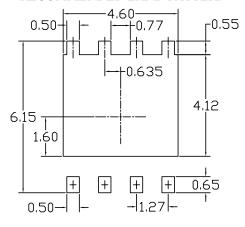






(SCALE 5:1)

RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES			
3 I MBOLS	MIN	NOM	MAX	MIN	NOM	MAX	
A	0.85	0. 95	1.00	0.033	0.037	0.039	
A1	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
С	0. 15	0. 20	0. 25	0.006	0.008	0.010	
D	4. 80	5. 20	5. 30	0. 201	0. 205	0. 209	
D1	4. 25	4. 35	4. 45	0. 167	0.171	0. 175	
Е	5. 45	5. 55	5. 65	0. 215	0. 219	0. 222	
E1	5. 95	6.05	6. 15	0. 234	0. 238	0. 242	
E2	3. 525	3. 625	3. 725	0. 139	0. 143	0. 147	
E3	1. 175	1. 275	1. 375	0.046	0.050	0.054	
e	1. 27 BSC			0.050 BSC			
L	0.45	0. 55	0.65	0.018	0.022	0.026	
L1	0		0. 15	0		0.006	
L2	0.68 REF			0.027 REF			
θ	0°		10°	0°		10°	

NOTE

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SEMICONDUCTOR

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm





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